

January 2008

# FDC855N

# Single N-Channel, Logic Level, PowerTrench® MOSFET 30V, 6.1A, 27m $\Omega$

#### **Features**

- Max  $r_{DS(on)} = 27m\Omega$  at  $V_{GS} = 10V$ ,  $I_D = 6.1A$
- Max  $r_{DS(on)} = 36m\Omega$  at  $V_{GS} = 4.5V$ ,  $I_D = 5.3A$
- SuperSOT<sup>TM</sup> -6 package: small footprint (72% smaller than standard SO-8; low profile (1mm thick).
- RoHS Compliant

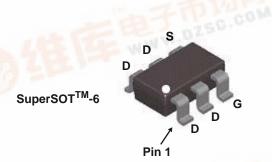


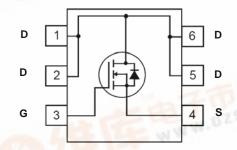
#### **General Description**

This N-Channel Logic Level MOSFET is an efficient solution for low voltage and battery powered applications. Utilizing Fairchild Semiconductor's advanced PowerTrench® process, this device possesses minimized on-state resistance to optimize the power consumption. They are ideal for applications where in-line power loss is critical.

#### **Application**

■ Power Management in Notebook, Hard Disk Drive





## **MOSFET Maximum Ratings** T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			30	V
V <sub>GS</sub>	Gate to Source Voltage			±20	V
	Drain Current -Continuous	T <sub>A</sub> = 25°C	(Note 1a)	6.1	_
-Pulsed				20	A
D	Power Dissipation (Steady State)		(Note 1a)	1.6	10/
$P_{D}$	Power Dissipation (Steady State)		(Note 1b)	0.8	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Ra	nge		-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	(Note 1)	30	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	78	C/VV

#### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
.855	FDC855N	SuperSOT-6	7"	8 mm	3000 units

# **Electrical Characteristics** T<sub>J</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	ncteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, referenced to 25°C		24		mV/°C
1	Zero Gate Voltage Drain Current	$V_{GS} = 0V, V_{DS} = 24V,$			1	
IDSS	Zero Gate Voltage Drain Current	T <sub>C</sub> = 125°C			250	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA

#### On Characteristics

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.0	2.0	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, referenced to 25°C		-6		mV/°C
r <sub>DS(on)</sub> Static Drain		$V_{GS} = 10V, I_D = 6.1A$		20.7	27.0	
	Static Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 5.3A$		28.2	36.0	mΩ
		$V_{GS} = 10V$ , $I_D = 6.1A$ , $T_J = 125$ °C		30.1	39.3	
g <sub>FS</sub>	Forward Transconductance	$V_{DD} = 10V, I_D = 6.1A$		20		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 45V V 0V	493	655	pF
Coss	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$ $f = 1MHz$	108	145	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1101112	62	95	pF
$R_q$	Gate Resistance	f = 1MHz	1.0		Ω

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		6	12	ns
t <sub>r</sub>	Rise Time	$V_{DD} = 15V, I_D = 6.1A,$ $V_{GS} = 10V, R_{GEN} = 6\Omega$	2	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 6\Omega$	14	23	ns
t <sub>f</sub>	Fall Time		2	10	ns
$Q_{g}$	Total Gate Charge at 10V	V <sub>GS</sub> =0Vto10V	9.2	13	nC
$Q_{g}$	Total Gate Charge at 5V	$V_{GS} = 0V \text{ to } 5V$ $V_{DD} = 15V,$ $I_{D} = 6.1A$	4.9	7.0	nC
$Q_{gs}$	Gate to Source Charge	I <sub>D</sub> = 6.1A	1.7		nC
$Q_{ad}$	Gate to Drain "Miller" Charge		3.1		nC

#### **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 1.3A (Note 2)	0.80	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 6.1A. di/dt = 100A/us	17	31	ns
Q <sub>rr</sub>	Reverse Recovery Charge	1F = 0.1A, αί/αι = 100A/μS	6	12	nC

#### Notes

1:  $R_{\theta JA}$  is the sum of the junction-to-case and case-to- ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a. 78°C/W when mounted on a 1 in² pad of 2 oz copper.



 b. 156°C/W when mounted on a minimum pad of 2 oz copper.

2: Pulse Test: Pulse Width < 300  $\mu$ s, Duty Cycle < 2.0%.

# Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

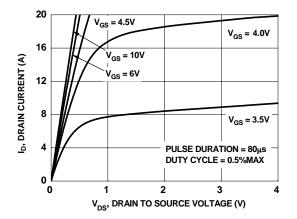


Figure 1. On-Region Characteristics

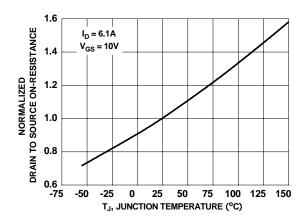


Figure 3. Normalized On-Resistance vs Junction Temperature

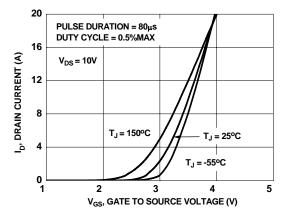


Figure 5. Transfer Characteristics

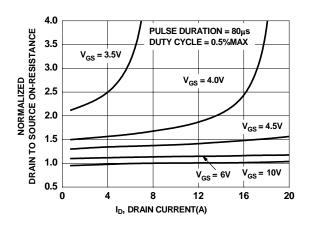


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

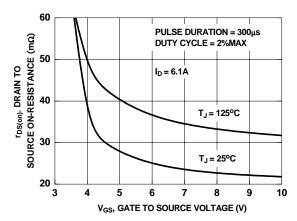


Figure 4. On-Resistance vs Gate to Source Voltage

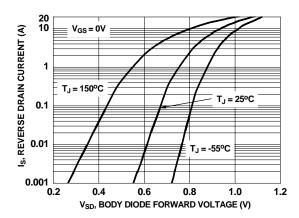


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

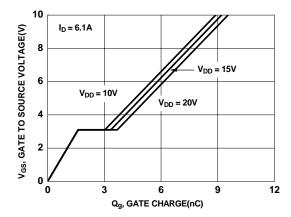
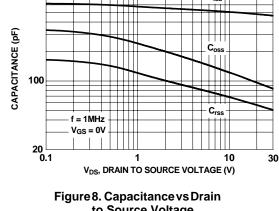


Figure 7. Gate Charge Characteristics



1000

to Source Voltage

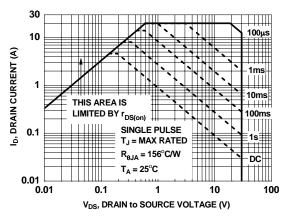


Figure 9. Forward Bias Safe **Operating Area** 

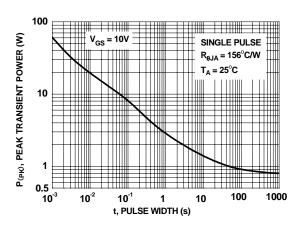


Figure 10. Single Pulse Maximum Power Dissipation

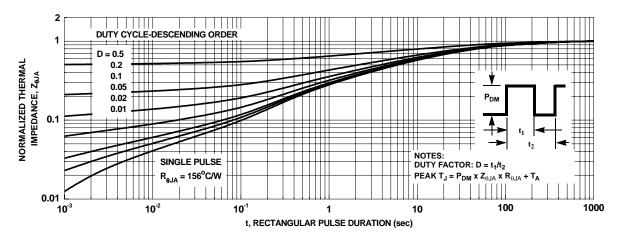
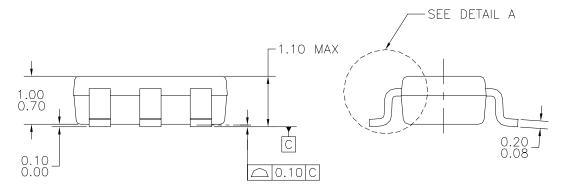
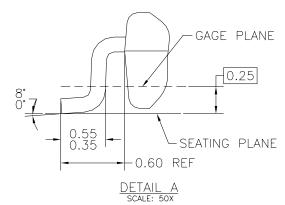


Figure 11. Transient Thermal Response Curve

# **Dimensional Outline and Pad Layout** SYMM 0.95 -0.95 3.00 2.80 A 1.00 MIN 6 4 В 3.00 2.60 2.60 1.70 1.50 3 0.50 0.30 0.95 0.70 MIN+ ◆ 0.20 C A B 1.90 LAND PATTERN RECOMMENDATION





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NOTES: UNLESS OTHERWISE SPECIFIED

- THIS PACKAGE CONFORMS TO JEDEC MO-193. VAR. AA, ISSUE C, DATED JANUARY 2000. ALL DIMENSIONS ARE IN MILLIMETERS.





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